

# JEIDA Ver. 4 ONE TIME PROGRAMMABLE ROM

## VARIATION

Part Number	Memory Size	Description
OWB065SD *0	64K Bytes	32K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
OWB129SD *0	128K Bytes	64K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
OWB257SD *0	256K Bytes	128K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
OWB513SD *0	512K Bytes	256K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD
OWB101SD *0	1M Bytes	512K × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD (Under development)
OWB201SD *0	2M Bytes	1M × 16 bits JEIDA Ver.4 CMOS OTP ROM CARD (Under development)

Note: \* : Attribute memory type  
 X : 2K Bytes EEPROM (can be read/written)  
 Y : No attribute memory (output “FF”) (read only)

## OUTLINE OF FUNCTIONS AND FEATURES

- (1) This memory card conforms to JEIDA Ver.4.
- (2) Size of the card
  - Width : 54.0 mm
  - Length : 85.6 mm
  - Thickness : 3.3 mm
- (3) Includes exclusive IC's for the control of I/O.
- (4) Support 2 type attribute memory.
  - 4-1) With 2K Bytes EEPROM which can be read/written.
  - 4-2) No attribute memory which can be read only. (output “FF”)
- (5) This card is programmed by manufacturer.
- (6) Card type: 68 pin two-piece type.

## MAXIMUM RATING

Symbol	Description	Note	Min	Max	Unit
VCC	Supply voltage		-0.5	7.0	V
VIN	Input signal voltage	1	-0.5	VCC + 0.5	V
VOUT	Output signal voltage	1	-0.5	VCC	V
TOPR	Operating temperature		0	60	°C
TSTR	Storage temperature		-20	60	°C
HUM	Humidity	2	10	90	%
PD	Power dissipation			2.0	W
VPP	Program supply voltage		-0.5	14.0	V

- Notes: 1. Under 7.0 V  
2. No dew condition

## CAPACITANCE (Ta = 25°C, VIN/VOUT = 0 V, f = 1 MHz)

Symbol	Description	Min	Typ	Max	Unit
C1	Input capacitance		10	14	pF
C2	Input/output capacitance		10	14	pF

Note: The above figures are for reference only

## RECOMMENDED DC OPERATING CONDITIONS

Symbol	Description	Min	Typ	Max	Unit
VCC	Supply voltage at read	4.75	5.0	5.25	V
VPP	Supply at read	4.75	5.0	5.25	V
VIH	High level input voltage	3.5	—	VCC + 0.3	V
VIL	Low level input voltage	-0.3	—	1.0	V

**DC ELECTRICAL CHARACTERISTICS (VCC = 5 V, Ta = 25°C)**

Symbol	Description	Note	Condition	Min	Typ	Max	Unit
ILI	Low level input current	1,3	VIN = 0 V	-10	—	10	μA
		2		-53	—	-48	μA
IHI	High level input current	1, 2	VIN = 5 V	-10	—	10	μA
		3		10	—	50	μA
VOH	High level output voltage	3	IOH = -2.0 mA	VCC -0.4	—	—	V
VOL	Low level output voltage	3	IOL = 6.0 mA	—	—	VSS +0.4	V

- Notes:
- A0 to A20
  - $\overline{CE1}$ ,  $\overline{CE2}$ ,  $\overline{WE}$ ,  $\overline{OE}$ ,  $\overline{REG}$   
Pull-up to VCC through 100K ohm
  - D0 to D15  
Pull-down to GND through 100K ohm

**CURRENT CONSUMPTION (Ta = 25°C, VCC = 5 V ±5%)**

Symbol	Description	Condition		Min	Typ	Max	Unit
ISTBY	Standby current	$\overline{CE} = \overline{WE} = \overline{OE} = \overline{REG} =$ VCC -0.2 V Other = VIL/VIH		—	1.0	1.5	mA
IACT	Active current (read)	$\overline{CE} = V_{IL}$ , IOUT = 0 mA, Other = VIL/VIH	f = 1 MHz	—	20	40	mA
			f = MAX	—	—	70	mA
IPP	VPP current (read)	VPP = VCC ±0.25 V		-20	—	20	μA

## OPERATING MODES (READ) OF COMMON MEMORY

Mode	REG	A0	$\overline{CE1}$	$\overline{CE2}$	$\overline{OE}$	WE	D0 to D7	D8 to D15
Standby	*	*	V <sub>IH</sub>	V <sub>IH</sub>	*	*	HZ	HZ
Even data read	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	OUTPUT	HZ
Odd data read 1	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	OUTPUT	HZ
Odd data read 2	V <sub>IH</sub>	*	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	HZ	OUTPUT
Word read	V <sub>IH</sub>	*	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	OUTPUT	OUTPUT

- Notes : HZ = High impedance  
(Pull-down to GND through 100K ohm)
- \* = Input is V<sub>IH</sub> or V<sub>IL</sub>
- V<sub>PP</sub> = V<sub>CC</sub> ± 0.25 V

## OPERATING MODES OF ATTRIBUTE MEMORY

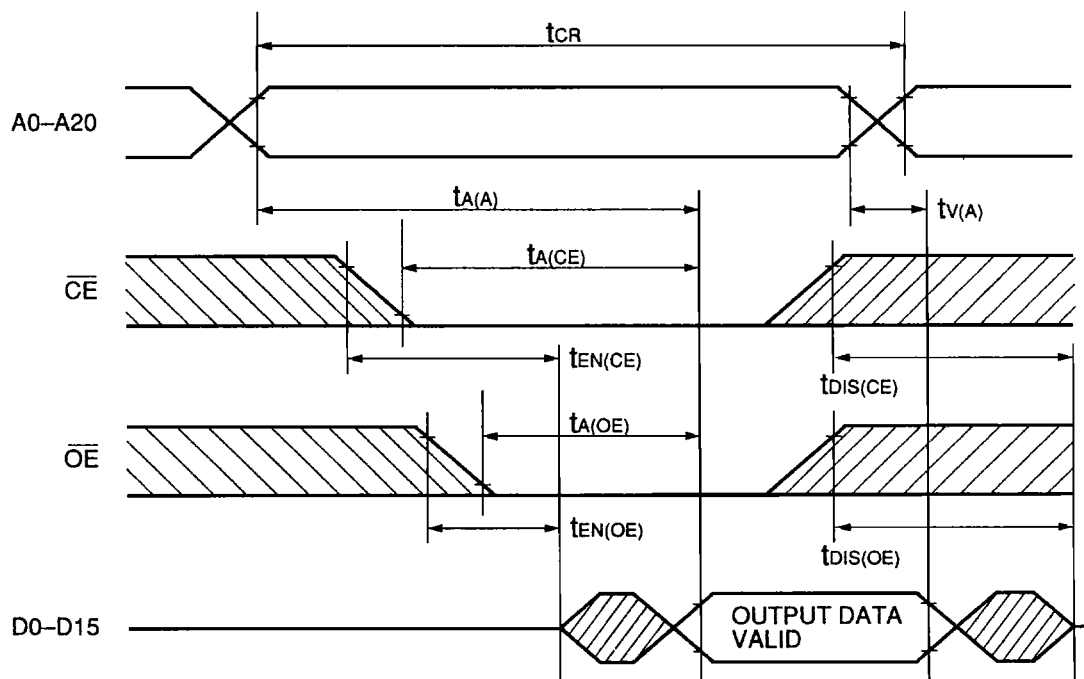
Mode	REG	A0	A1 to A11	$\overline{CE1}$	$\overline{CE2}$	$\overline{OE}$	WE	D0 to D7	D8 to D15
Data read	V <sub>IL</sub>	V <sub>IL</sub>	*	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	OUTPUT	HZ
	V <sub>IL</sub>	V <sub>IH</sub>	*	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IH</sub>	HZ	HZ
Word data read	V <sub>IL</sub>	*	*	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	OUTPUT	HZ
Data write	V <sub>IL</sub>	V <sub>IL</sub>	*	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	INPUT	don't care
	V <sub>IL</sub>	V <sub>IH</sub>	*	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	don't care	don't care
Word data write	V <sub>IL</sub>	*	*	V <sub>IL</sub>	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>IL</sub>	INPUT	don't care

- Notes: HZ = High impedance  
(Pull-down to GND through 100K ohm)
- \* = Input is V<sub>IH</sub> or V<sub>IL</sub>

## AC ELECTRICAL CHARACTERISTICS AT READ OF COMMON MEMORY

Symbol	Parameter	Min	Max	Unit
TCR	Read cycle time	250	—	ns
TA (A)	Address access time	—	250	ns
TA (CE)	Card enable access time	—	250	ns
TA (OE)	Output enable access time	—	125	ns
TDIS (CE)	Output disable time from card enable	—	100	ns
TDIS (OE)	Output disable time from output enable	—	100	ns
TEN (CE)	Output enable time from card enable	5	—	ns
TEN (OE)	Output enable time from output enable	5	—	ns
TV (A)	Valid data hold time from address invalid	0	—	ns

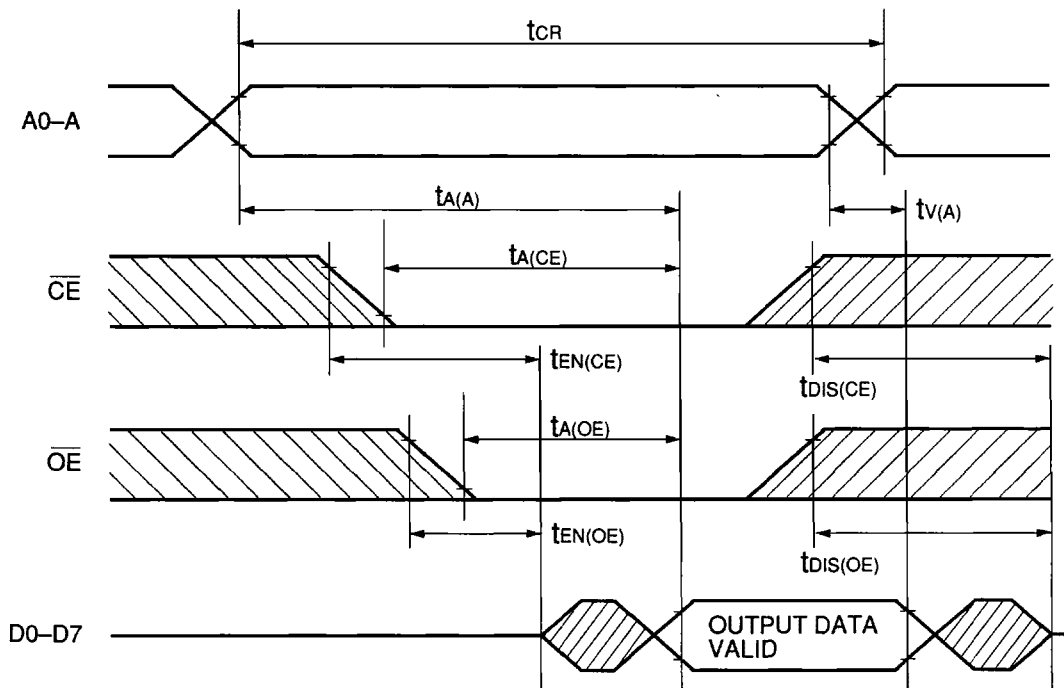
## READ TIMING OF COMMON MEMORY



**AC ELECTRICAL CHARACTERISTICS AT READ OF ATTRIBUTE MEMORY**

Symbol	Parameter	Min	Max	Unit
TCR	Read cycle time	300	—	ns
TA (A)	Address access time	—	300	ns
TA (CE)	Card enable access time	—	300	ns
TA (OE)	Output enable access time	—	150	ns
TDIS (CE)	Output disable time from card enable	—	100	ns
TDIS (OE)	Output disable time from output enable	—	100	ns
TEN (CE)	Output enable time from card enable	5	—	ns
TEN (OE)	Output enable time from output enable	5	—	ns
TV (A)	Valid data hold time from address invalid	0	—	ns

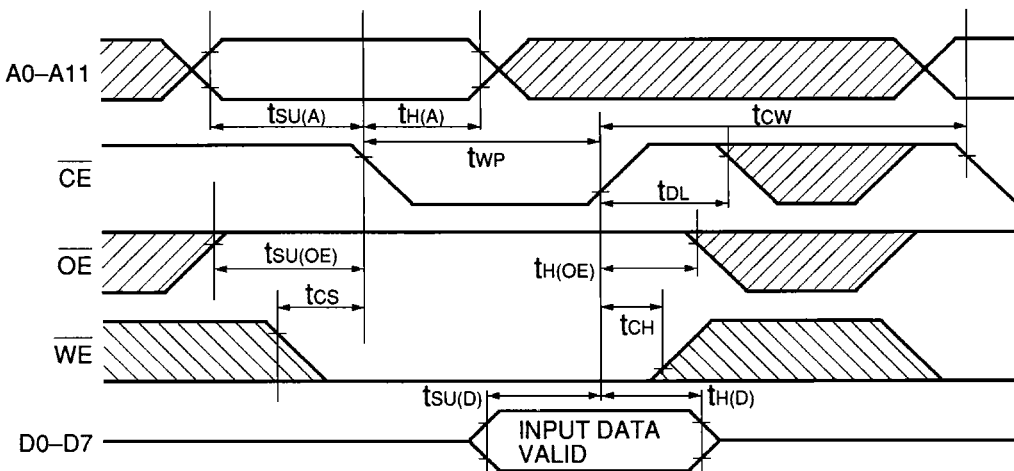
**READ TIMING OF ATTRIBUTE MEMORY**



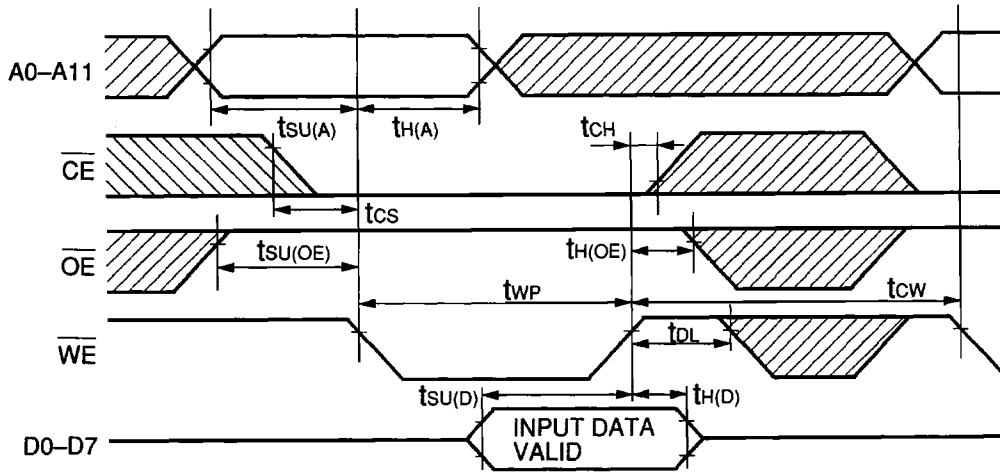
**WRITE CYCLE OF ATTRIBUTE MEMORY  
(2K Bytes EEPROM ATTRIBUTE MEMORY)**

Symbol	Parameter	Min	Max	Unit
TCW	Write cycle time	15	—	ms
TWP	Write pulse width	150	—	ns
TSU(A)	Address setup time	30	—	ns
TSU(D)	Data setup time	80	—	ns
TH(D)	Data hold time	30	—	ns
TSU(OE)	Output enable setup time	15	—	ns
TH(OE)	Output enable hold time	15	—	ns
TH(A)	Address hold time	100	—	ns
TCS	Write setup time	30	—	ns
TCH	Write hold time	0	—	ns
TDL	Data latch time	50	—	ns

**WRITE TIMING OF ATTRIBUTE MEMORY ( $\overline{CE}$  CONTROLLED WRITE)  
(2K Bytes EEPROM ATTRIBUTE MEMORY)**



**WRITE TIMING OF ATTRIBUTE MEMORY ( $\overline{\text{WE}}$  CONTROLLED WRITE)  
(2K Bytes EEPROM ATTRIBUTE MEMORY)**



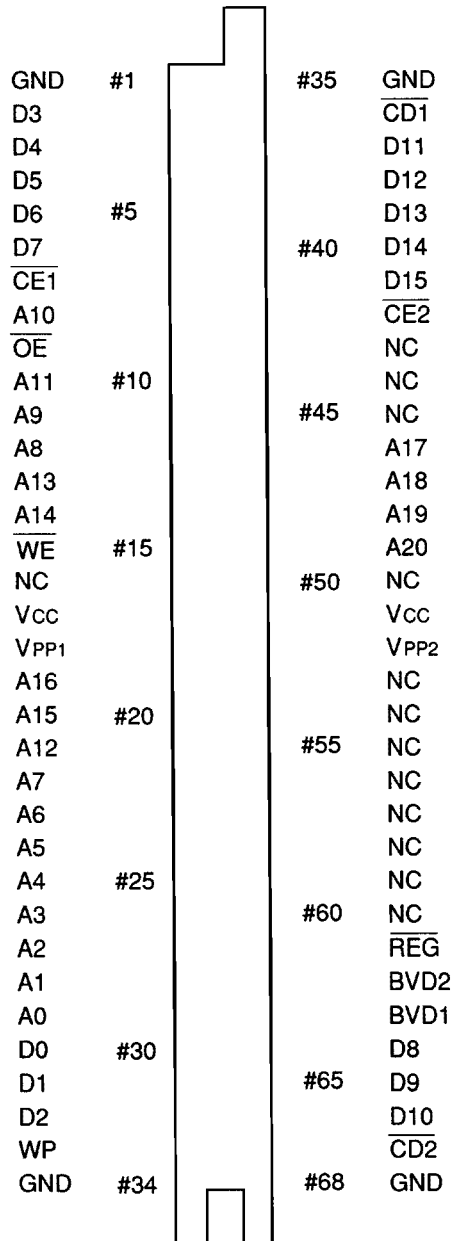
<< AC test conditions >>

Output load

: 1 TTL gate + 100 pF (include jig)



**PIN ASSIGNMENT**



## PIN ASSIGNMENT

Pin No.	Symbol	Pin No.	Symbol	Pin No.	Symbol
1	GND	23	A6	46	A17*
2	D3	24	A5	47	A18*
3	D4	25	A4	48	A19*
4	D5	26	A3	49	A20*
5	D6	27	A2	50	NC
6	D7	28	A1	51	VCC
7	$\overline{CE1}$	29	A0	52	VPP2
8	A10	30	D0	53	NC
9	$\overline{OE}$	31	D1	54	NC
10	A11	32	D2	55	NC
11	A9	33	WP**	56	NC
12	A8	34	GND	57	NC
13	A13	35	GND	58	NC
14	A14	36	$\overline{CD1}$	59	NC
15	$\overline{WE}$	37	D11	60	NC
16	NC	38	D12	61	$\overline{REG}$
17	VCC	39	D13	62	BVD2**
18	VPP1	40	D14	63	BVD1**
19	A16	41	D15	64	D8
20	A15	42	$\overline{CE2}$	65	D9
21	A12	43	NC	66	D10
22	A7	44	NC	67	$\overline{CD2}$
		45	NC	68	GND

Notes \*A17 : OWB257, OWB513, OWB101, OWB201

\*A18 : OWB513, OWB101, OWB201

\*A19 : OWB101, DWB201

\*A20 : OWB201

NC = No connect

\*\*WP, BVD1, BVD2: this line is connected to VCC inside the card.